

FORM PTO 1449 (modified)

ATTY DOCKET NO. 862.C2217

APPLICATION NO. 09/845,297

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

October 15, 2001

APPLICANT Akihiro NAKAUCHI et al.

FILING DATE May 1, 2001

GROUP 2851

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AM	5,774,205	06/30/1998	Sato	355	67	07/18/1996
AM	5,973,316	10/26/1999	Ebbesen et al.	250	216	11/26/1997

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AM	11-072607	03/16/1999	Japan	—	—	Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	1	Flanders, D.C. and Henry I. Smith. "A new interferometric alignment technique," <i>Applied Physics Letters</i> , Vol. 31, No. 7, October 1997. Pp. 426-428.
AM	1	Roychoudhuri, C. "Chapter 6: Multiple-Beam Interferometers," <i>Optical Shop Testing, Second Edition</i> , Ed. by Daniel Malacara, John Wiley & Sons: 1992. Pp. 207-245.

EXAMINER

Alan Mathews

DATE CONSIDERED

1-11-2002

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1